

Notice of References Cited	Application/Control No. 09/782,751	Applicant(s)/Patent Under Reexamination LUNDBY, STEIN A.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,539,728 A	07-1996	Gaiani et al.	370/342
*	B	US-5,542,107 A	07-1996	Kay, Stanley E.	455/513
*	C	US-5,740,168 A	04-1998	Nakamura et al.	370/347
*	D	US-5,799,005 A	08-1998	Soliman, Samir S.	370/335
*	E	US-5,809,422 A	09-1998	Raleigh et al.	455/449
*	F	US-5,828,659 A	10-1998	Teder et al.	370/328
*	G	US-5,881,368 A	03-1999	Grob et al.	455/69
*	H	US-5,884,196 A	03-1999	Lekven et al.	455/574
*	I	US-5,887,023 A	03-1999	Mabuchi, Tetsuo	375/133
*	J	US-5,893,035 A	04-1999	Chen, Tao	455/522
*	K	US-5,943,362 A	08-1999	Saito, Naritoshi	375/143
*	L	US-5,982,760 A	11-1999	Chen, Tao	370/335
*	M	US-6,014,565 A	01-2000	Bonta, Jeffrey D.	455/437

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-RE36,591 E	02-2000	Hayashi et al.	370/342
*	B	US-6,035,196 A	03-2000	Hengeveld et al.	455/437
*	C	US-6,038,220 A	03-2000	Kang et al.	370/252
*	D	US-6,044,070 A	03-2000	Valentine et al.	370/316
*	E	US-6,034,971 A	03-2000	Love et al.	370/468
*	F	US-6,067,458 A	05-2000	Chen, Tao	455/522
*	G	US-6,070,085 A	05-2000	Bender et al.	455/522
*	H	US-6,058,107 A	05-2000	Love et al.	370/332
*	I	US-6,072,990 A	06-2000	Agrawal et al.	455/69
*	J	US-6,075,974 A	06-2000	Saints et al.	455/69
*	K	US-6,072,778 A	06-2000	Labeledz et al.	370/252
*	L	US-6,085,106 A	07-2000	Sendonaris et al.	455/522
*	M	US-6,112,080 A	08-2000	Anderson et al.	455/422.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,137,789 A	10-2000	Honkasalo, Zhichun	370/342
*	B	US-6,151,512 A	11-2000	Chheda et al.	455/562.1
*	C	US-6,144,646 A	11-2000	Bohlmann et al.	370/311
*	D	US-6,160,999 A	12-2000	Chheda et al.	455/69
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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